High-Resolution Multi-Channel FPGA-TDC Architectures

Eugen Bayer, Nikolaus Kurz

e.bayer@gsi.de

FPGA-TDC:

- Fast development process
- Flexible (Clock frequency, resolution/channel Nr. trade-off)
- Adaptable (Special needs, e.g: extra large FIFOs for bursts)

Previous work in this field, e.g.:

- 1997: Kalisz, Altera Quick Logic, 200 ps resolution
- 2008: J.Wu, Altera-Cyclone-II, 10 ps RMS
- 2009: Favi, Virtex-5, ~ 17 ps resolution
- 2010: Bayer, Virtex-4, 9 ps RMS

Time Measurement

Sampling with system clock:

- Only one FF per channel.
- Uncertainty: sys_clk_period

The Nutt method:

- 1 Stage: Counter
- 2 Stage: Interpolator



Interpolation Methods – Tapped Delay Lines







Interpolation Methods – Ring Oscillators







Interpolation Methods – Vernier Method



6

Vernier + Nutt Method



Here: timestamp_A= timestamp_B \rightarrow $T_P = T_A - T_B$

7

Interpolation Methods in FPGAs

Ring Oscillator based:

- Difficult to implement due to routing delay unpredictability.
- Non stochastic jitter of the RO-Signal \rightarrow Large accumulated jitter.
- Implementation of multi channel TDCs based on the Vernier-RO method is complex and time consuming.

Tapped Delay Lines based:

- A large effort was done by the vendors to distribute the system clock signal on the FPGA die with the minimal skew.
- On modern FPGAs many dedicated carry lines are available which are designed to be as fast as possible to implement fast carry adders.
- \rightarrow TDL method 1 can be implemented with the minimal effort on time.



Tapped Delay Lines in FPGA

FPGA:

- The "Carry-Chain" serves as a delay chain
- Carry-Chain multiplexers are the delay elements
- Delay (max.) = 45 ps (Virtex-4: CIN→COUT = 90 ps, speed grade 10)
- Real delays vary → cell-by-cell calibration necessary





Wave Union Method



- Two or more transitions propagate.
- If one transition is in an ultra wide bin, then the other is in a normal bin.
- Store a pattern of edges
- Trigger them simultaneously
 - \rightarrow Control the runtime of signals (difficult but feasible)

Calibration

- Can be done in software or hardware (inside FPGA)
- Hardware \rightarrow additional resources needed
- Software:
 - Saves resources for additional channels
 - Simple algorithm:
 - 1. Code Density Test (uncorrelated cal. signal or book real hits)
 - 2. Calculate the width of each bin in ps

$$w_i = \frac{n_i}{N} \cdot 5000 \, ps$$
 $N = total number$

3. Construct the Conversion-LUT:

$$b_i = \left(\sum_{k=1}^{i-1} w_k\right) + \frac{w_i}{2}$$

Design (one TDC-channel, simplified)

- TDL method extended with "Wave Union" method [Wu]
- Pipelined design
- Dead time > 15 ns (depends on needed resolution).
- Puffer for 512 hits per channel.
- Real rate depends on readout interface.



Measurements

TDC

LVDS- Fanout

(1 ps)

RND-Pulse-

Generator

Measured:

1. Root Mean Square RMS = 1

$$\sum_{i=1}^{N} (x_i - \overline{x})^2$$

N

- 2. Temperature dependence
- 3. Dependence on the supply voltage variations
- 4. Crosstalk

Measurement setup:

- Delay between 2 rising edges on different channels
- ~ 250k measurements / setup.
- Delays < 1 ns were adjusted via different cable lengths
- Delays > 1 ns were adjusted with the Tektronix Data Timing Generator (precision = 1 ps)
- Measurement value: prop. status + timestamp
- Calibration and analysis offline





RMS



Test reading: ٠

2.

3.

wire length channel A	mean [ps]	RMS [ps]
~6 cm	1697	9
~7 cm	1740	9
~8 cm	1781	9

DTG time diff. [ns]	mean [ps]	RMS [ps]
42	45798	9
44	47798	9
46	49798	9
1004	1005795	11
1006	1007797	11
1008	1009798	11



RMS - improved



Temperature Variation

- Temperature region: 30 °C 85 °C in 5°C steps.
- Observations:
 - 1. Deformation of the calibration LUTs.
 - 2. Measured distance in delay elements changes, but...
 - ...no change of the calibrated value of the RMS, if calibration LUT is up-todate. (acceptable region: ± 5°C)
- Conclusion:

No significant effect!



Core Voltage Variation

- Region : 1.15 V 1.25 V
- Observations:
 - 1. Deformation of the calibration LUTs
 - 2. 2 ps increase of the RMS value
 - 3. 40 ps shift of the mean in the whole region
- Conclusion:
 - The voltage has to be stabilized
 - Worst case ± 12 mV

 \rightarrow ca. 7 ps

• (Normal case: ± 2 mV)



Crosstalk



- No crosstalk under normal conditions
- Prove of sensitivity with enforced crosstalk (flat band cable)
- → NO CROSS TALK INSIDE FPGA

- 50 channels (10 ps RMS) on XC4VLX40 with 40k logic cells.
- 10 channels (3.6 ps RMS) on the same FPGA @ 50% resource usage.
- \rightarrow Geometry of the FPGA die is also a factor.
- Up to 200k logic cells on one FPGA in this FPGA family.
- Resource usage decreases in newer FPGA families due to optimized FPGA architecture.



Resolution

- Dead time: 10 ns @ 16 ps RMS $\leftarrow \rightarrow$ 50 ns @ 3.6 ps RMS or >1 GHz with a reduced number of channels.
- No. of ch.: depends on FPGA (~ up to 128 of 10 ps RMS ch.)
- Resolution: 3.6 ps RMS resolution achievable

High flexibility!

FPGA-TDC (GSI):

 ~48 channels with 9 ps RMS or 32 channels with 5 ps RMS for a time interval measurement, dead time: 3 cycles @ 200 MHz = 15 ns.

FPGA-TDC (J.Wu):

- 18 channels with 25 ps RMS, dead time: 2 cycles @ 400 MHz
- 8 channels with 10 ps RMS, dead time: 18 cycles @ 400 MHz HP-TDC (CERN):
 - 32 channels with 30 ps resolution
 - 8 channels with 17 ps resolution

TDC-GPX (ACAM):

- 8 channels with 27 ps resolution, 200 MHz max. Hit rate (40 MHz continuous)
- 2 channels with 10 ps resolution, dead time 18 cycles, 500 kHz continuous hit rate

Thanks for your attention!